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Proceedings of the Fourth Asian Test Symposium: November 23-24. Proceedings of the Fourth Asian Test Symposium: November 23-24, 1995: Bangalore, India by Unknown Author. Paperback 9780818671296 Proceedings Of The Fourth Asian Test Symposium, November 23-24. 9780818671296 Proceedings Of The Fourth Asian Test Symposium. Patent WO2004001433A1 - Electronic circuit with asynchronously. Jan 30, 2001. 96CH35932, Proceedings of. 33rd Design Automation Conference, Repetitive Sub—circuits”, Test Symposium, 1995, Proceedings of the Fourth Asian Bangalore, India Nov. 23—24, 1995,. Los Alamitos, CA, USA, IEEE Full list of publications - Rice University Monarch Research Group @proceedingsDBLP:confats1995, title 4th Asian Test Symposium ATS '95, November 23-24, 1995. Bangalore, India, booktitle Asian Test Symposium, IEEE Computer Society Press fourth asian test symposium bangalore india. Proceedings Of The Fourth Asian Test Symposium, November 23-24, 1995. 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